

30V, 199A, 1.9mΩ N-channel Power SGT MOSFET

JMSL0302PG

Features

- $\bullet \ \ \,$ Excellent $R_{DS(ON)}$ and Low Gate Charge
- 100% UIS TESTED
- 100% ΔVds TESTED
- Halogen-free; RoHS-compliant
- Pb-free plating

Applications

- Load Switch
- PWM Application
- Power Management

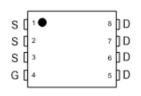
Product Summary

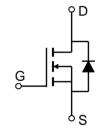
Parameters	Value	Unit
V_{DSS}	30	V
$V_{GS(th)_Typ}$	1.6	V
I _D (@V _{GS} =10V)	199	Α
$R_{DS(ON)_Typ}(@V_{GS}=10V$	1.3	mΩ
$R_{DS(ON)_Typ}(@V_{GS}=4.5V$	1.9	mΩ











PDFN5x6-8L

Pin Assignment

Schematic Diagram

Ordering Information

Device	Marking	MSL	Form	Package	Reel(pcs)	Per Carton (pcs)
JMSL0302PG	SL0302P	1	Tape&Reel	PDFN5x6-8L	5000	50000

Absolute Maximum Ratings (@ T_C = 25°C unless otherwise specified)

Symbol	Parameter		Value	Unit
V_{DS}	Drain-to-Source Voltage		30	V
V_{GS}	Gate-to-Source Voltage		±20	V
	Continuous Drain Current	$T_C = 25$ °C	199	А
I _D	Continuous Diain Current	$T_C = 100$ °C	141	A
I _{DM}	Pulsed Drain Current (1)		Refer to Fig.4	Α
E _{AS}	Single Pulsed Avalanche Energy (2)		277	mJ
P _D		$T_C = 25^{\circ}C$	122	w
		$T_C = 100$ °C	49	VV
T_{J} , T_{STG}	Junction & Storage Temperature Range		-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Max	Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient ⁽³⁾	42	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.0	C/VV



Electrical Characteristics (T_J = 25°C unless otherwise specified)

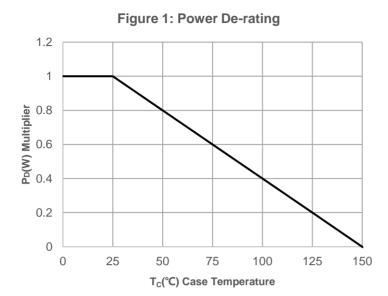
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Cha	racteristics			,		ļ
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24V, V_{GS} = 0V$	-	-	1.0	μА
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA
On Cha	racteristics			-		-
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.1	1.6	2.1	V
D	Static Drain-Source ON-Resistance ⁽⁴⁾	$V_{GS} = 10V, I_D = 20A$	-	1.3	1.8	mΩ
$R_{DS(ON)}$	Static Drain-Source ON-Resistance	$V_{GS} = 4.5V, I_D = 15A$	-	1.9	2.7	mΩ
Dynami	c Characteristics					
R_{g}	Gate Resistance	f = 1MHz	-	1.1	-	Ω
C_{iss}	Input Capacitance	24 24 454	-	3237	-	pF
C _{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 15V,$ f = 1MHz	-	2268	-	pF
C _{rss}	Reverse Transfer Capacitance	1 - 11/11/2	-	207	-	pF
Q_g	Total Gate Charge	V 0 40V	-	51	-	nC
Q_{gs}	Gate Source Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{DS} = 15V, I_{D} = 15A$	-	9	-	nC
Q_{gd}	Gate Drain("Miller") Charge	■ V _{DS} = 13V, I _D = 13A	-	11	-	nC
Switchi	ng Characteristics					
$t_{d(on)}$	Turn-On DelayTime	_	-	24	-	ns
t _r	Turn-On Rise Time	$V_{GS} = 10V, V_{DD} = 15V$	-	55	-	ns
$t_{\text{d(off)}}$	Turn-Off DelayTime	I_D = 15A, R_{GEN} = 6.2Ω	-	36	-	ns
t _f	Turn-Off Fall Time		-	35	-	ns
Body D	iode Characteristics					
I_S	Maximum Continuous Body Diode Forward Current		-	-	199	Α
I _{SM}	Maximum Pulsed Body Diode Forward Current		-	-	797	А
V _{SD}	Body Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 20A$	-		1.2	V
trr	Body Diode Reverse Recovery Time	1 1EA di/d+ 100A/	-	56	-	ns
Qrr	Body Diode Reverse Recovery Charge	$I_F = 15A$, di/dt = 100A/us	-	62.2	-	nC

Notes:

- 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.
- 2. E_{AS} condition: Starting T_J =25C, V_{DD} =15V, V_G =10V, R_G =25ohm, L=3mH, I_{AS} =13.58A, V_{DD} =0V during time in avalanche.
- 3. $R_{\theta JA}$ is measured with the device mounted on a 1inch $^{\!2}$ pad of 2oz copper FR4 PCB.
- 4. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 0.5%.



Typical Performance Characteristics



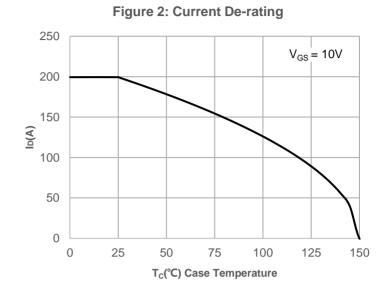
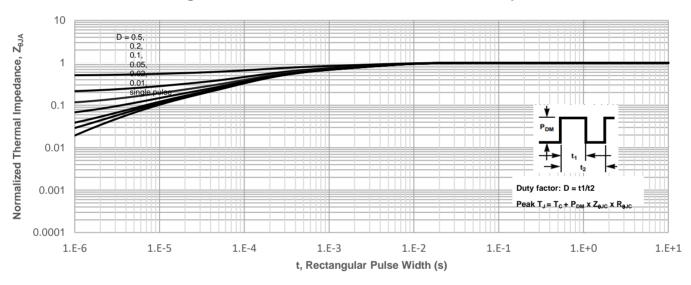
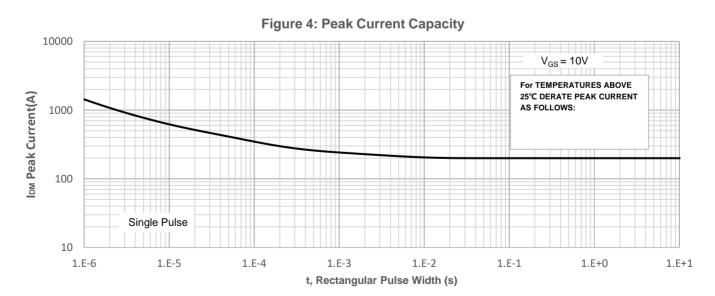


Figure 3: Normalized Maximum Transient Thermal Impedance







Typical Performance Characteristics

Figure 5: Output Characteristics

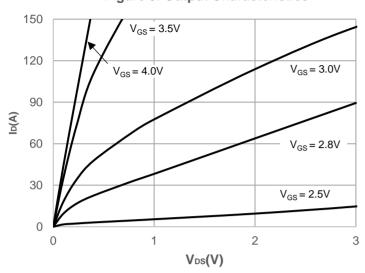


Figure 6: Typical Transfer Characteristics

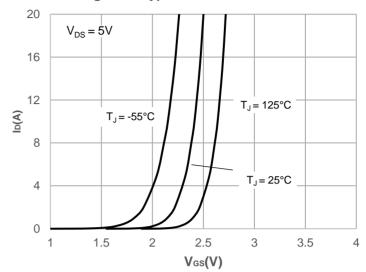


Figure 7: On-resistance vs. Drain Current

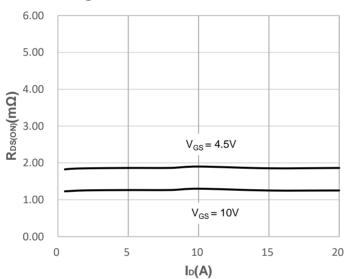


Figure 8: Body Diode Characteristics

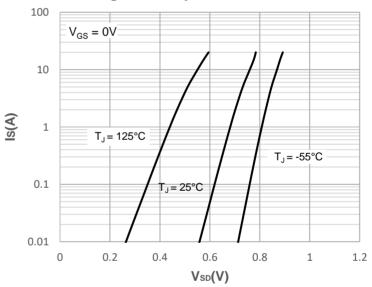


Figure 9: Gate Charge Characteristics

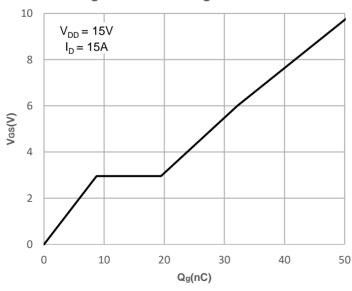
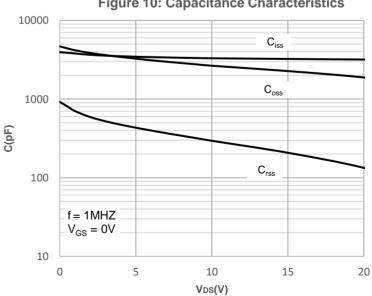


Figure 10: Capacitance Characteristics





Typical Performance Characteristics

Figure 11: Normalized Breakdown voltage vs. Junction Temperature

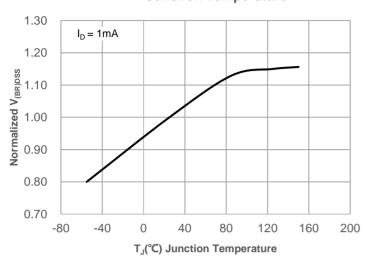


Figure 13: Normalized Threshold Voltage vs. Junction Temperature

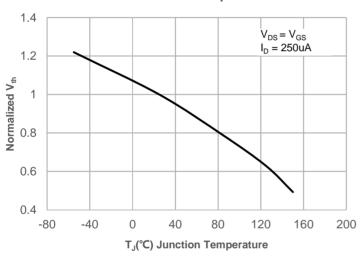


Figure 15: Maximum Safe Operating Area

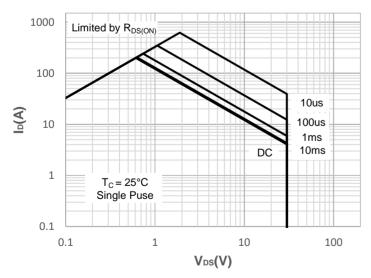
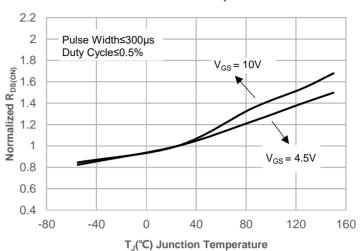
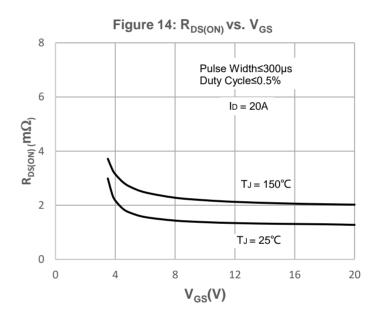


Figure 12: Normalized on Resistance vs. Junction Temperature







Test Circuit

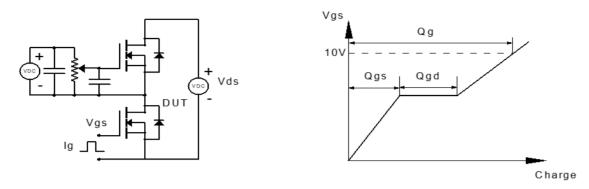


Figure 1: Gate Charge Test Circuit & Waveform

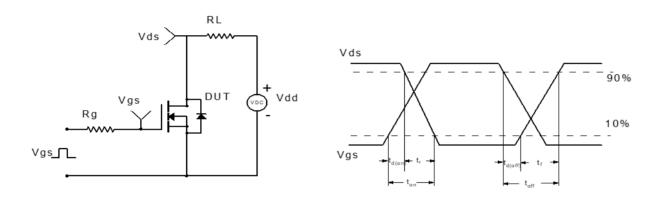


Figure 2: Resistive Switching Test Circuit & Waveform

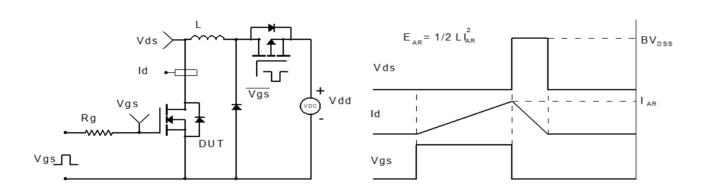


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

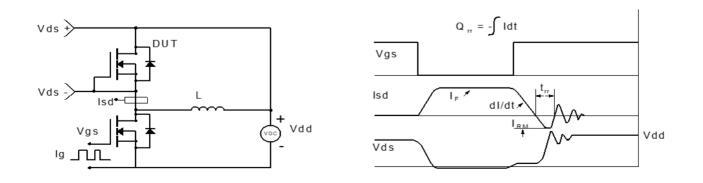
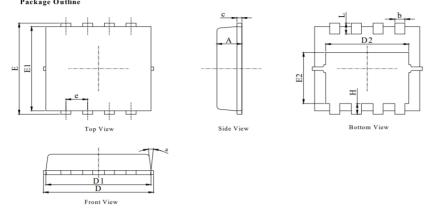


Figure 4: Diode Recovery Test Circuit & Waveform

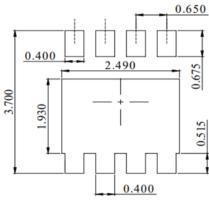


Package Mechanical Data(PDFN5X6-8L)



NOTES: 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M,1994. 2. ALL DIMNESIONS IN MILLIMETER (ANNGLE IN DEGREE). 3. DIMENSIONS OF A DE LI DO NOT INCLUDE MOLD FLASH PROTRUSIONS OF GATE BURRS.					
DTM		MILLIMETER			
DIM.	MIN.	NOM.	MAX.		
A	0. 90	1.00	1. 10		
b	0.31	0. 41	0. 51		
С	0. 20	0. 25	0.30		
D	5. 00	5. 20	5. 40		
D1	4.95	5. 05	5. 15		
D2	4.00	4. 10	4. 20		
Е	6.05	6. 15	6. 25		
E1	5. 50	5. 60	5. 70		
E2	3. 42	3. 53	3. 63		
е	1. 27BSC				
Н	0.60	0.70	0.80		
L	0. 50	0.70	0.80		
K	1. 23 REF				
θ	-	-	10°		

Recommended Soldering Footprint



DIMENSIONS: MILLIMETERS

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